

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	4259	29/593,832,854.ccls.	US-PGPUB; USPAT; JPO; DERWENT	OR	ON	2006/01/04 10:17
S2	2362	test\$3 near (print\$2 near circuit near board)	US-PGPUB; USPAT; JPO; DERWENT	OR	ON	2006/01/04 10:18
S3	135	(test\$3 near board) near (hole\$1 or via\$1)	US-PGPUB; USPAT; JPO; DERWENT	OR	ON	2006/01/04 10:19
S5	13	S2 and S3	US-PGPUB; USPAT; JPO; DERWENT	OR	ON	2006/01/04 10:23
S6	1	S1 and S5	US-PGPUB; USPAT; JPO; DERWENT	OR	ON	2006/01/04 10:19
S7	2	su-sung-ling.in.	US-PGPUB; USPAT; JPO; DERWENT	OR	ON	2006/01/04 10:20
S8	1379	dedicat\$3 near test\$2	US-PGPUB; USPAT; JPO; DERWENT	OR	ON	2006/01/04 10:22
S9	42	S2 and S8	US-PGPUB; USPAT; JPO; DERWENT	OR	ON	2006/01/04 10:22
S10	1	S3 and S9	US-PGPUB; USPAT; JPO; DERWENT	OR	ON	2006/01/04 10:22
S11	1	S5 and S9	US-PGPUB; USPAT; JPO; DERWENT	OR	ON	2006/01/04 10:22
S12	5	("5698990").URPN.	USPAT	OR	ON	2006/01/04 10:36
S13	13	("4017793"   "4322682"   "4625164"   "4644269"   "4686468"   "4700132"   "4739257"   "4749945"   "4906920"   "5068600"   "5227718"   "5252916"   "5396186").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/04 10:40

S14	8	conduct\$3 near rubber near pressure near sensitive	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/04 10:42
S15	13804	test\$2 near (fix\$4 or board\$1)	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/04 10:41
S16	0	S14 and S15	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/04 10:41
S17	0	S2 aND S14	US-PGPUB; USPAT; JPO; DERWENT	OR	ON	2006/01/04 10:42

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» Key

IEEE JNL IEEE Journal or Magazine

IEEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

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- 1. A multilayer board-type magnetic field probe with high spatial resolution estimation method for ICs**
- 
- Masuda, N.; Tamaki, N.; Wabuka, H.; Watanabe, T.; Ishizaka, K.;
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- Electromagnetic Compatibility, 1999 International Symposium on
- 
- 17-21 May 1999 Page(s):801
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- Digital Object Identifier 10.1109/ELMAGC.1999.801460
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